

7th Belle II VXD Workshop and 18th International Workshop on DEPFET Detectors and Applications

Wednesday, 21 January 2015

PXD Parallel Session I: DEPFET Sensor - Lecture hall T1, Building T, Faculty of Mathematics and Physics, Charles University in Prague (16:00 - 16:45)

-Conveners: Rainer Richter

time	[id] title	presenter
16:00	[62] Comparison study of the influence of oxide thickness on the internal amplification	RUMMEL, Stefan
16:15	[63] Internal Amplification vs Oxide Thickness - Simulation results	RICHTER, Rainer
16:30	[64] Pilot run - production status	RICHTER, Rainer

PXD Parallel Session I: EMCM and gated mode tests - Lecture hall T1, Building T, Faculty of Mathematics and Physics, Charles University in Prague (16:45 - 18:00)

-Conveners: Christian Koffmane

time	[id] title	presenter
16:45	[53] Metallization of the EMCM 3 & 4 wafers	Mr KLOSE, Daniel
17:00	[54] Pilot run - test results after first metal	Dr AVELLA, Paola
17:10	[58] PXD9 IV Curves	RICHTER, Rainer
17:20	[55] Gated Mode Tests with Hybrid 4.1	Mr PRINKER, Eduard
17:40	[56] Latest results of EMCM tests / measurements	Mr MUELLER, Felix